



Cascade Engineering Services, Inc.

# Viscoplastic Solder Fatigue Life Analysis

Reliability Engineering Group  
Cascade Engineering Services, Inc.  
6640 185th Ave NE Redmond WA 98052  
(425) 895-8617 x 564

[www.cascade-eng.com](http://www.cascade-eng.com)

# Solder Fatigue Life Analysis

## **Test Objective**

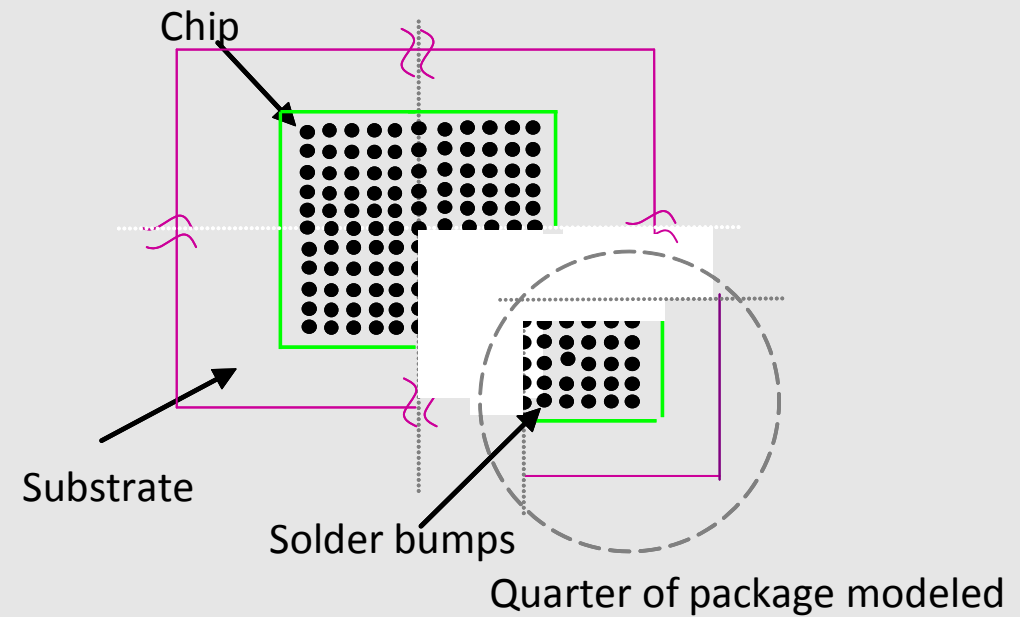
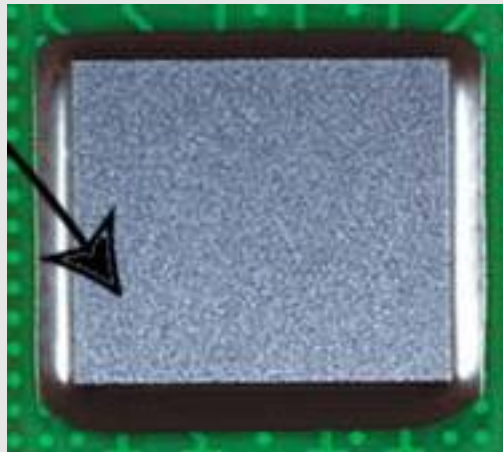
- To evaluate Solder joint fatigue life under thermal cycle loading

## **Methodology**

- Step 1: Geometry and Material Properties - Constitutive Material Models
- Step 2: Loads and Boundary Conditions
- Step 3: FEA Results
- Step 4: Fatigue Life Estimation
- Case Study Benefits

# Step 1: Geometric Model & Material Properties

## Flip-Chip Electronic Package



## Structure Dimensions

Components	Length (inch)	Width (inch)	Thickness (inch)
Chip	0.118	0.118	0.005315
Substrate	0.177	0.177	0.002756
Solder	Pitch: 0.009843	Max Dia: 0.003937	Standoff: 0.003543

# Step 1: Geometric Model & Material Properties

Components	Young's Modulus (Psi)	Poisson's Ratio	CTE (PPM / C)
Die	2.36e7	0.278	3.2
Substrate	3.5e6	0.3	16/16/35
Underfill	7.36e5	0.34	33
Solder	4.4e6	0.35	24.5
Passivation	4.7e7	0.24	2.9
Copper	1.7e7	0.3	16
Aluminum	1.01e7	0.24	23.2
Nickel	2.9e7	0.31	12.7

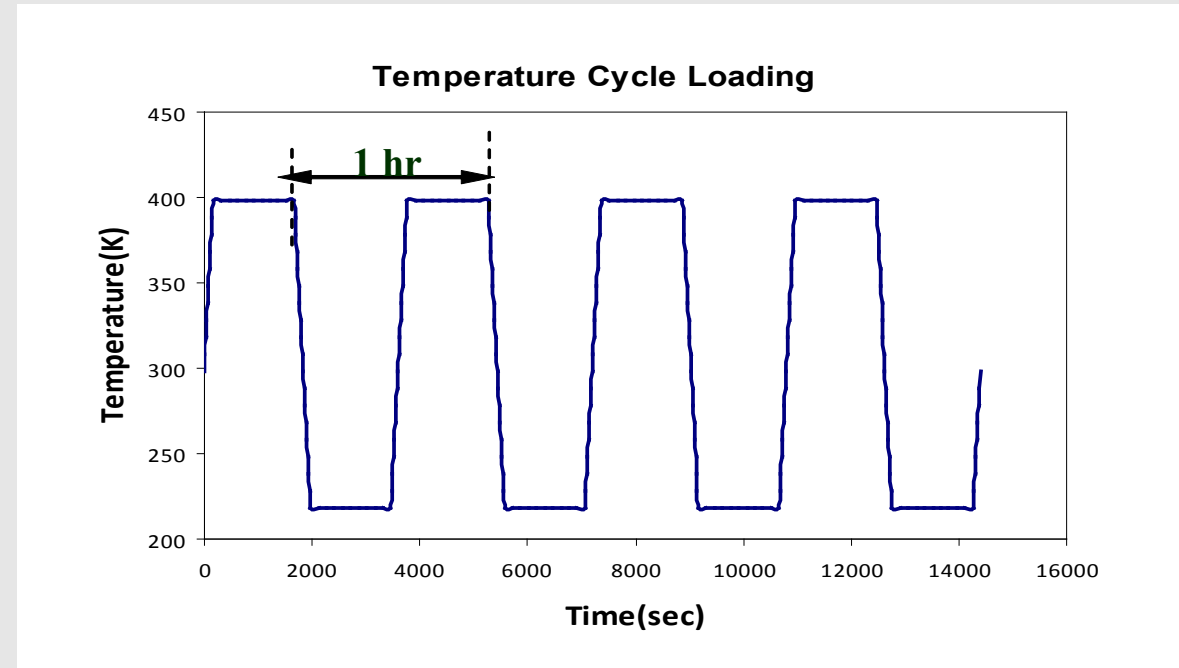
ANSYS	Parameter	Values	ANSYS	Parameter	Values
C1	$S_0$ (psi)	1800	C6	$h_0$ (psi)	2.0e5
C2	$Q/k(1/K)$	9400	C7	$S^{\wedge}$ (psi)	2.0e3
C3	$A(1/Sec)$	4.0e6	C8	n	0.07
C4	$\epsilon$	1.5	C9	a	1.3
C5	m	0.303			

## Solder: Anand Viscoplastic Constitutive Material Model

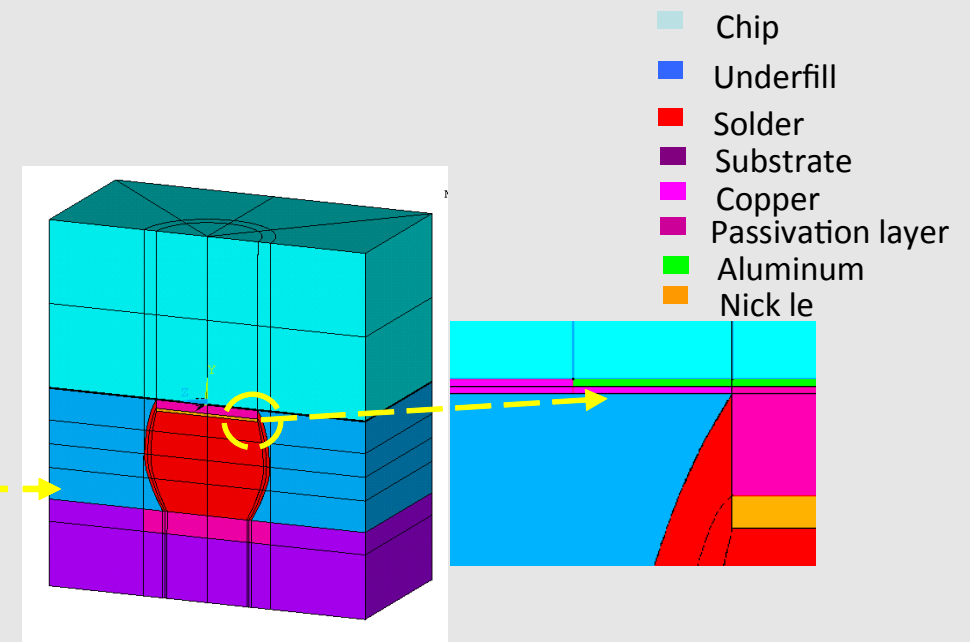
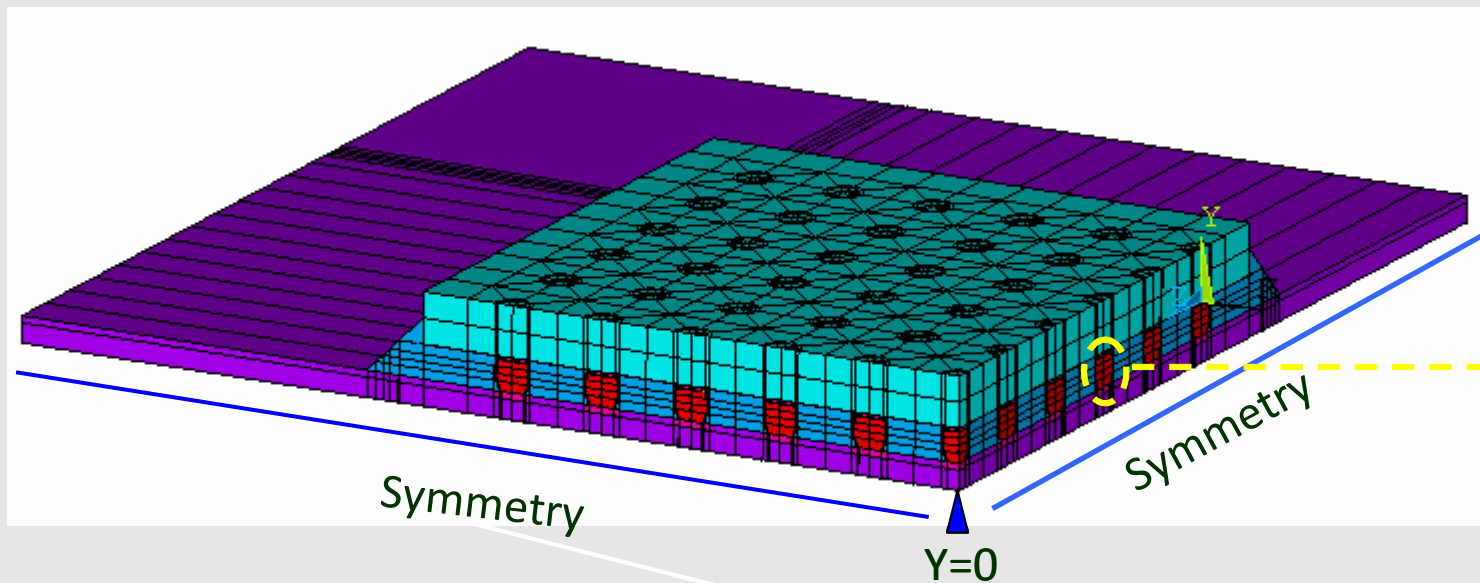
# Step 2: Loads & Boundary Conditions

## Thermal Loading

- Temperature limits: -55C to 125C
- Ramp rate: 36C / min
- Dwell time: 25 minutes



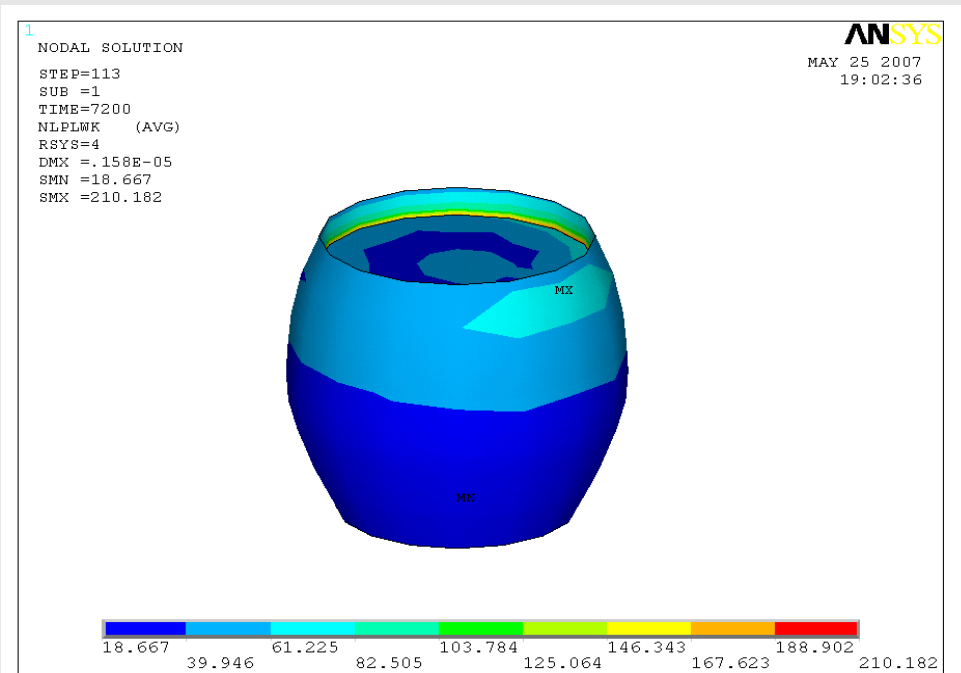
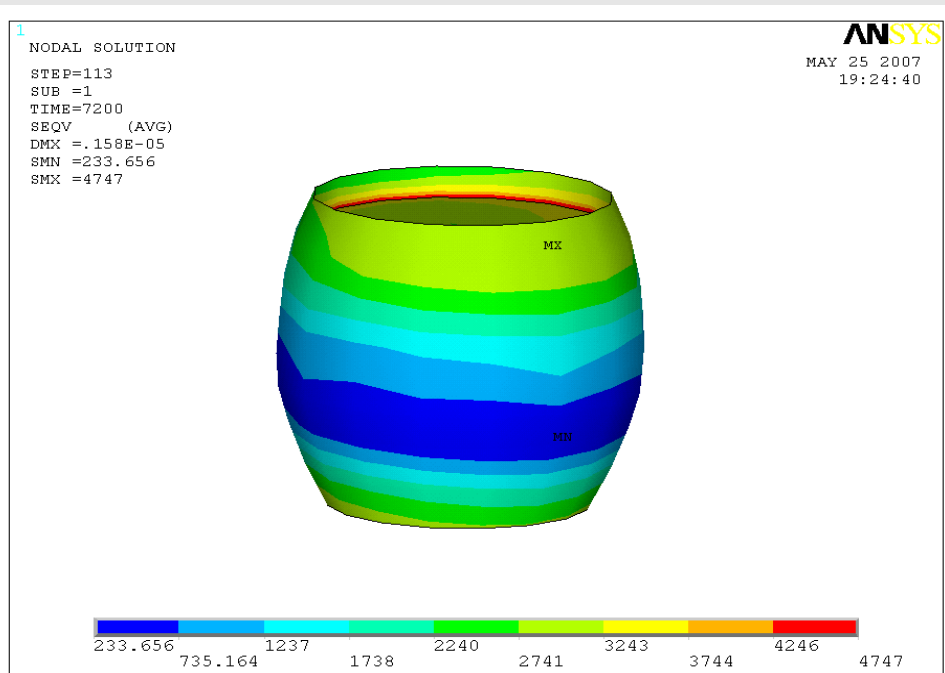
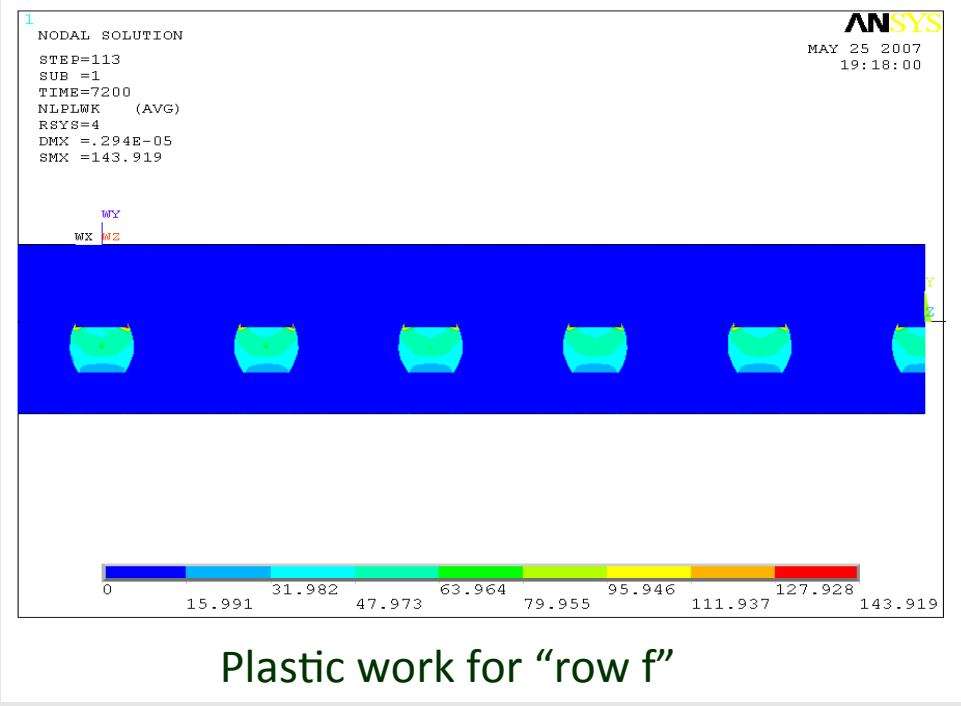
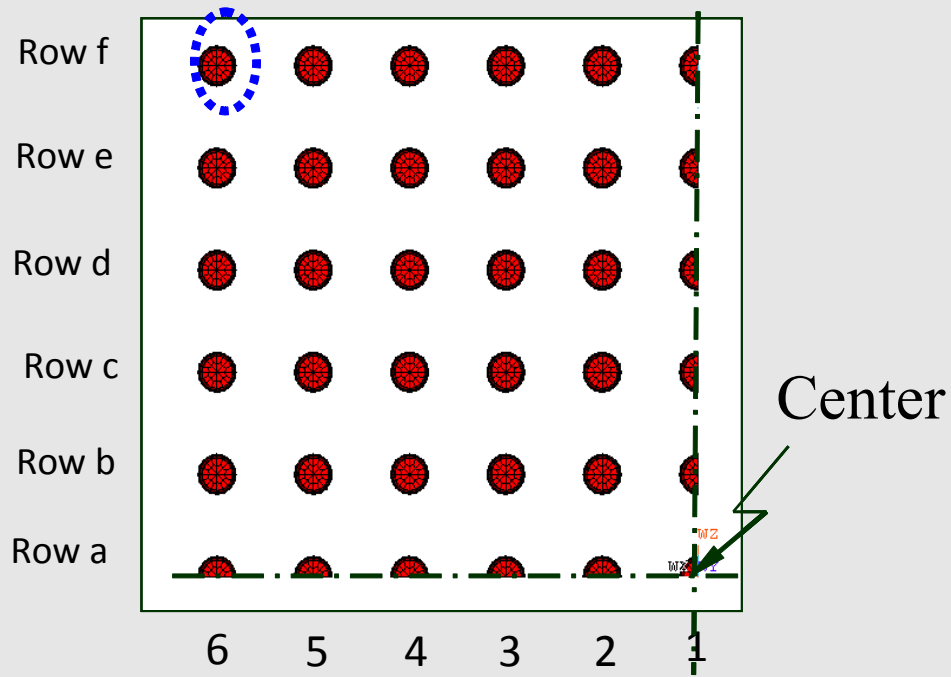
## 3-D Quarter Symmetric Model



Meshing and Boundary Conditions

Unit Model

# Step 3: FEA Results



# Step 4: Fatigue Life Estimation

## Solder Fatigue Life Model: Darveaux's Crack Growth Correlations

Characteristic life of the joint

$$\alpha = N_o + \frac{a}{\frac{da}{dN}}$$

Where,

$\Delta W_{avg}$  = Accumulated plastic work per cycle

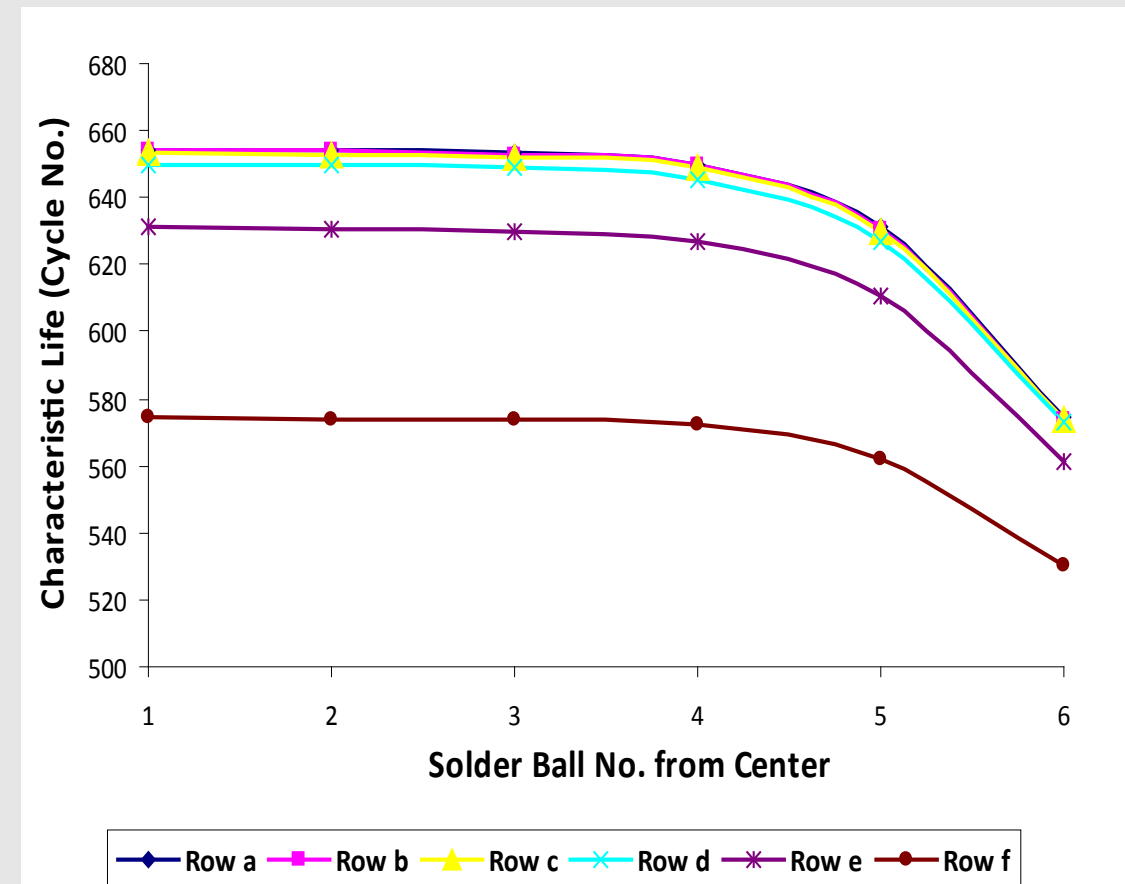
$N_o = K1(\Delta W_{avg})^{K2}$  = No. of cycles to crack initiation

$\frac{da}{dN} = K3(\Delta W_{avg})^{K4}$  = Crack growth rate

K1 , K2 , K3 , K4 = Crack growth constants

(for this case, K1=5.63e4, K2=1.62, K3=3.34e-7, K4=1.04)

a= the length of crack to propagate through the entire solder ball



**Characteristic life of solders at different locations**

# Case Study Benefits

## Summary

- Potential failure site: top of solder ball and below UBM layer
- Critical Solder Location: The corner solder ball “f6” is the most dangerous one with the shortest characteristic life of 530 cycles.
- Life Trends: Solder ball characteristic life decreased with increasing distance from center and life varied from 575-650 thermal cycles

## Benefits

- Thermal-mechanical stress analysis identified reliability risk areas
- Cost effective parametric studies assisted with a more robust and reliable product design
- Fast and economic way to evaluate solder fatigue life to complement time and cost intensive accelerated life tests
- Proven methodology for comparing different IC packaging styles, different suppliers for subsystem or system integration